

## Features

- High density cell design for ultra low  $R_{dson}$
- Fully characterized Avalanche voltage and current
- Good stability and uniformity with high EAS
- Excellent package for good heat dissipation
- Special process technology for high ESD capability

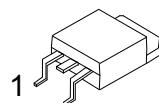
## Product Summary



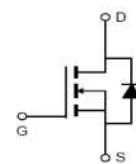
$V_{DS}$	30	V
$R_{DS(on),TYP} @ V_{GS}=10\text{ V}$	9	$\text{m}\Omega$
$I_D$	50	A

## Application

- Power switching application
- Hard switched and high frequency circuits
- Uninterruptible Power Supply



TO-252



N-Channel MOSFET

## Absolute Maximum Ratings ( $T_c=25^\circ\text{C}$ unless otherwise noted)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	$V_{DS}$	30	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	V
Drain Current-Continuous	$I_D$	50	A
Drain Current-Continuous( $T_c=100^\circ\text{C}$ )	$I_D(100^\circ\text{C})$	35	A
Pulsed Drain Current	$I_{DM}$	140	A
Maximum Power Dissipation	$P_D$	60	W
Derating factor		0.4	W/ $^\circ\text{C}$
Single pulse avalanche energy <sup>(Note 5)</sup>	$E_{AS}$	70	mJ
Operating Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 To 175	$^\circ\text{C}$

## Thermal Characteristic

Thermal Resistance,Junction-to-Case <sup>(Note 2)</sup>	$R_{\theta JC}$	2.5	$^\circ\text{C}/\text{W}$
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**Electrical Characteristics ( $T_c=25^\circ\text{C}$  unless otherwise noted)**

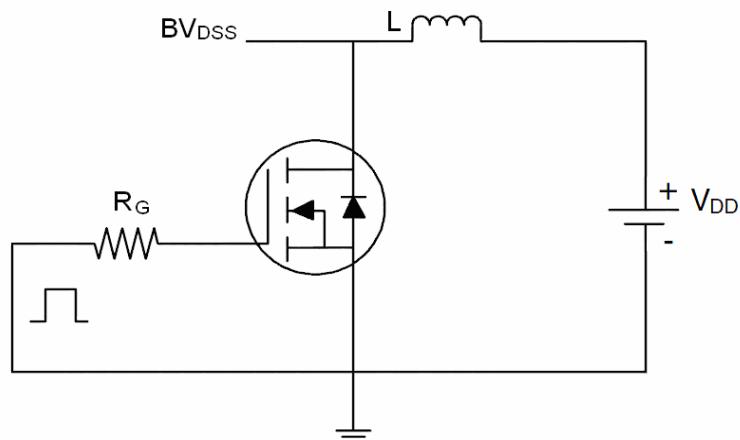
Parameter	Symbol	Condition	Min	Typ	Max	Unit
<b>Off Characteristics</b>						
Drain-Source Breakdown Voltage	$\text{BV}_{\text{DSS}}$	$\text{V}_{\text{GS}}=0\text{V}, \text{I}_D=250\mu\text{A}$	30	33	-	V
Zero Gate Voltage Drain Current	$\text{I}_{\text{DSS}}$	$\text{V}_{\text{DS}}=30\text{V}, \text{V}_{\text{GS}}=0\text{V}$	-	-	1	$\mu\text{A}$
Gate-Body Leakage Current	$\text{I}_{\text{GSS}}$	$\text{V}_{\text{GS}}=\pm 20\text{V}, \text{V}_{\text{DS}}=0\text{V}$	-	-	$\pm 100$	nA
<b>On Characteristics</b> <sup>(Note 3)</sup>						
Gate Threshold Voltage	$\text{V}_{\text{GS(th)}}$	$\text{V}_{\text{DS}}=\text{V}_{\text{GS}}, \text{I}_D=250\mu\text{A}$	1	1.4	2	V
Drain-Source On-State Resistance	$\text{R}_{\text{DS(ON)}}$	$\text{V}_{\text{GS}}=10\text{V}, \text{I}_D=25\text{A}$	-	9	11	$\text{m}\Omega$
		$\text{V}_{\text{GS}}=5\text{V}, \text{I}_D=20\text{A}$	-	11.3	14	
Forward Transconductance	$\text{g}_{\text{FS}}$	$\text{V}_{\text{DS}}=5\text{V}, \text{I}_D=20\text{A}$	15	-	-	S
<b>Dynamic Characteristics</b> <sup>(Note 4)</sup>						
Input Capacitance	$\text{C}_{\text{iss}}$	$\text{V}_{\text{DS}}=15\text{V}, \text{V}_{\text{GS}}=0\text{V},$ $F=1.0\text{MHz}$	-	2000	-	PF
Output Capacitance	$\text{C}_{\text{oss}}$		-	280	-	PF
Reverse Transfer Capacitance	$\text{C}_{\text{rss}}$		-	160	-	PF
<b>Switching Characteristics</b> <sup>(Note 4)</sup>						
Turn-on Delay Time	$t_{\text{d(on)}}$	$\text{V}_{\text{DD}}=15\text{V}, \text{I}_D=20\text{A}$ $\text{V}_{\text{GS}}=10\text{V}, \text{R}_{\text{GEN}}=1.8\Omega$	-	10	-	nS
Turn-on Rise Time	$t_r$		-	8	-	nS
Turn-Off Delay Time	$t_{\text{d(off)}}$		-	30	-	nS
Turn-Off Fall Time	$t_f$		-	5	-	nS
Total Gate Charge	$Q_g$	$\text{V}_{\text{DS}}=10\text{V}, \text{I}_D=25\text{A},$ $\text{V}_{\text{GS}}=10\text{V}$	-	23	-	nC
Gate-Source Charge	$Q_{gs}$		-	7	-	nC
Gate-Drain Charge	$Q_{gd}$		-	4.5	-	nC
<b>Drain-Source Diode Characteristics</b>						
Diode Forward Voltage <sup>(Note 3)</sup>	$\text{V}_{\text{SD}}$	$\text{V}_{\text{GS}}=0\text{V}, \text{I}_s=25\text{A}$	-	0.85	1.2	V
Diode Forward Current <sup>(Note 2)</sup>	$\text{I}_s$		-	-	50	A
Reverse Recovery Time	$t_{rr}$	$\text{TJ} = 25^\circ\text{C}, \text{IF} = 50\text{A}$ $d\text{i}/dt = 100\text{A}/\mu\text{s}$ <sup>(Note 3)</sup>	-	22	35	nS
Reverse Recovery Charge	$\text{Q}_{\text{rr}}$		-	11	18	nC
Forward Turn-On Time	$t_{\text{on}}$	Intrinsic turn-on time is negligible (turn-on is dominated by LS+LD)				

**Notes:**

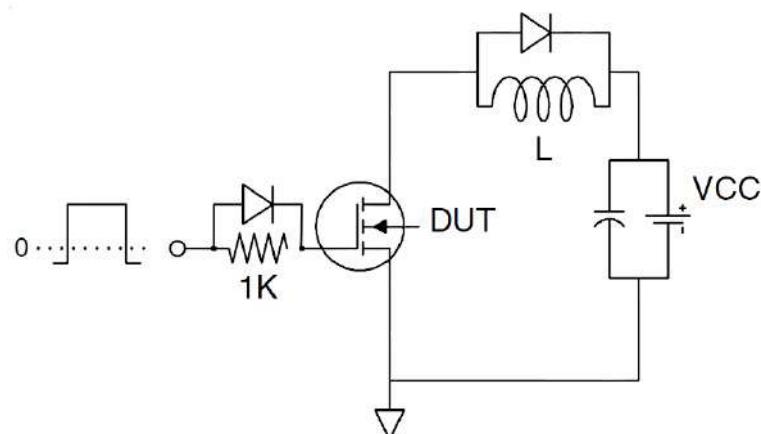
1. Repetitive Rating: Pulse width limited by maximum junction temperature.
2. Surface Mounted on FR4 Board,  $t \leq 10$  sec.
3. Pulse Test: Pulse Width  $\leq 300\mu\text{s}$ , Duty Cycle  $\leq 2\%$ .
4. Guaranteed by design, not subject to production
5. EAS condition:  $\text{Tj}=25^\circ\text{C}, \text{V}_{\text{DD}}=15\text{V}, \text{V}_{\text{G}}=10\text{V}, \text{L}=1\text{mH}, \text{R}_g=25\Omega$

## Test circuit

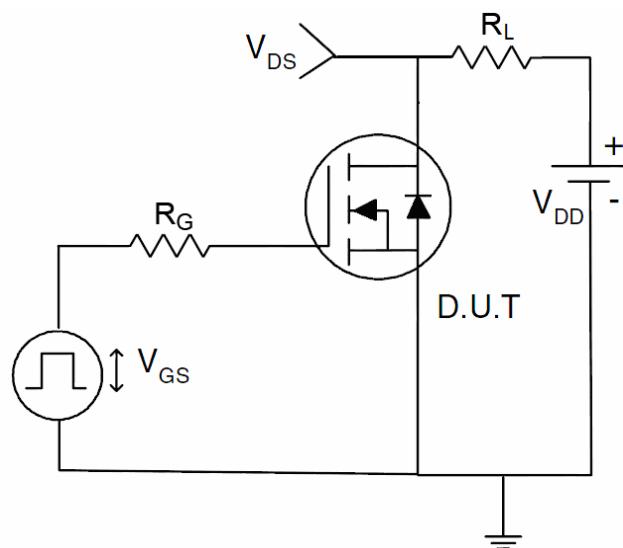
### 1) E<sub>AS</sub> test Circuits



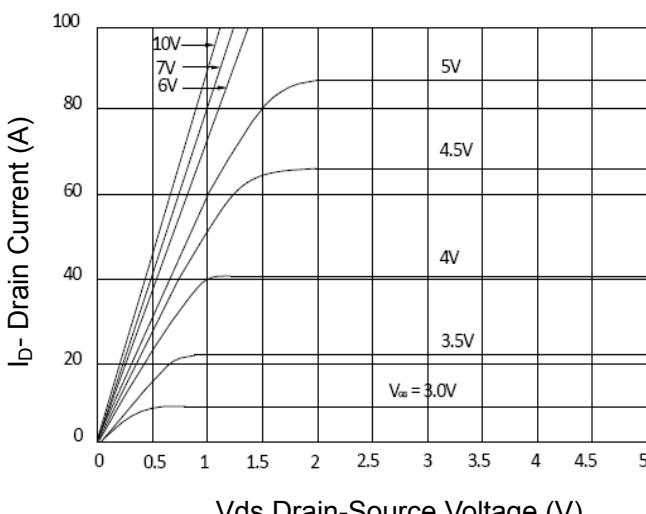
### 2) Gate charge test Circuit:



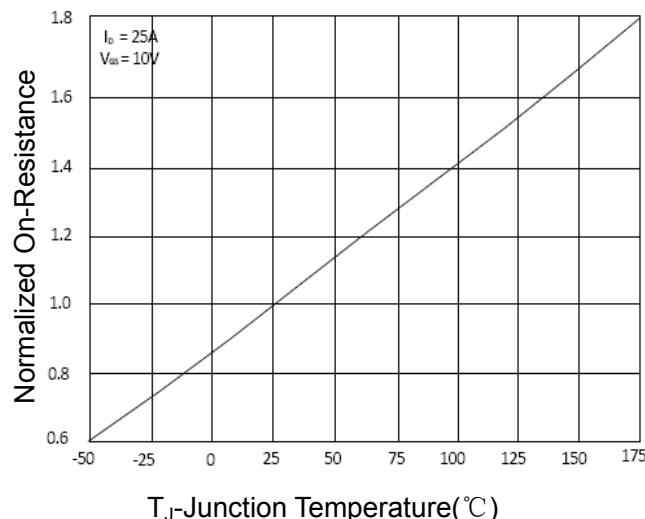
### 3) Switch Time Test Circuit:



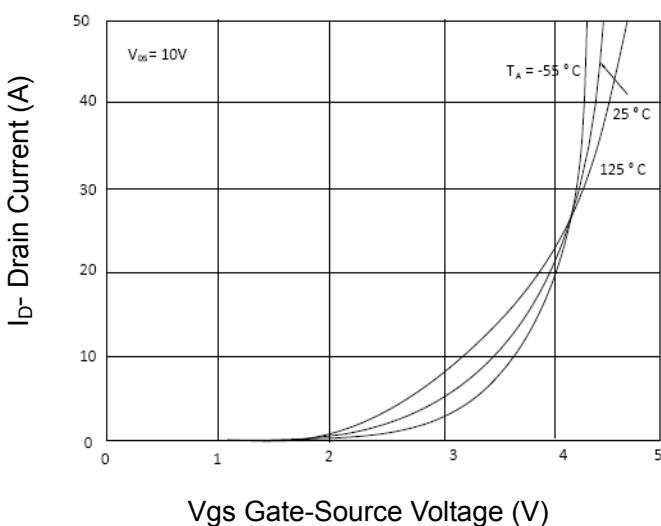
### Typical Electrical and Thermal Characteristics (Curves)



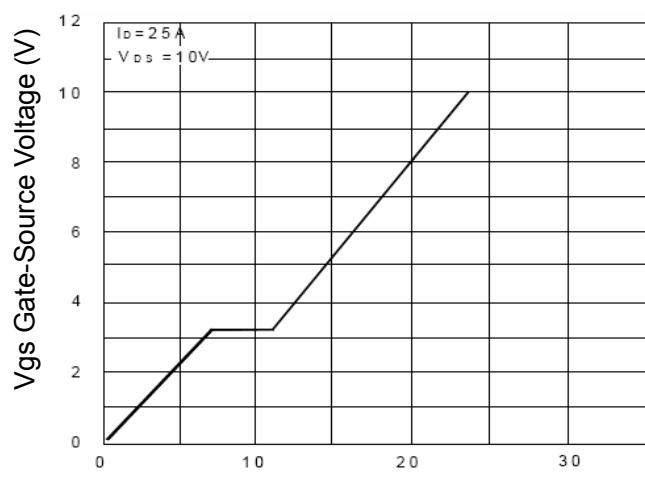
**Figure 1 Output Characteristics**



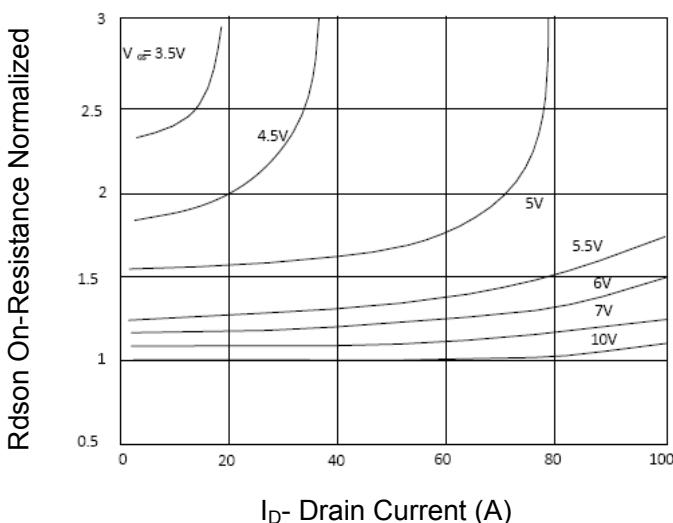
**Figure 4 Rdson-JunctionTemperature**



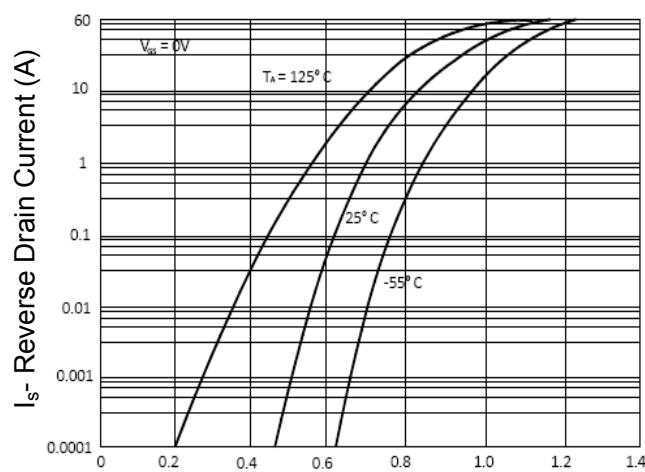
**Figure 2 Transfer Characteristics**



**Figure 5 Gate Charge**



**Figure 3 Rdson- Drain Current**



**Figure 6 Source- Drain Diode Forward**



ASCENDSEMI

ASDM3050KQ

30V N-Channel MOSFET

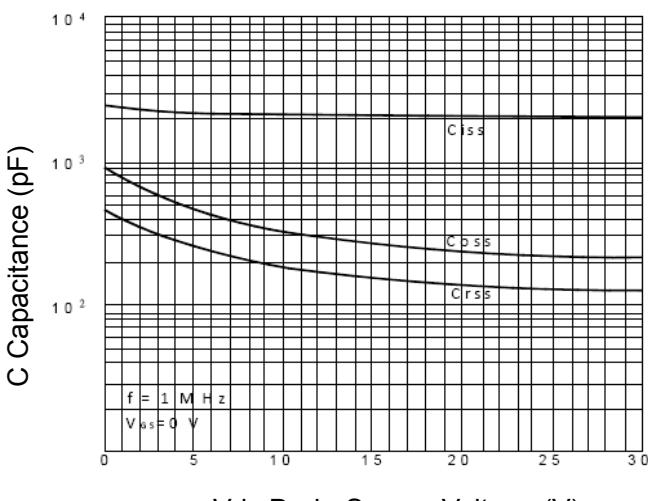


Figure 7 Capacitance vs Vds

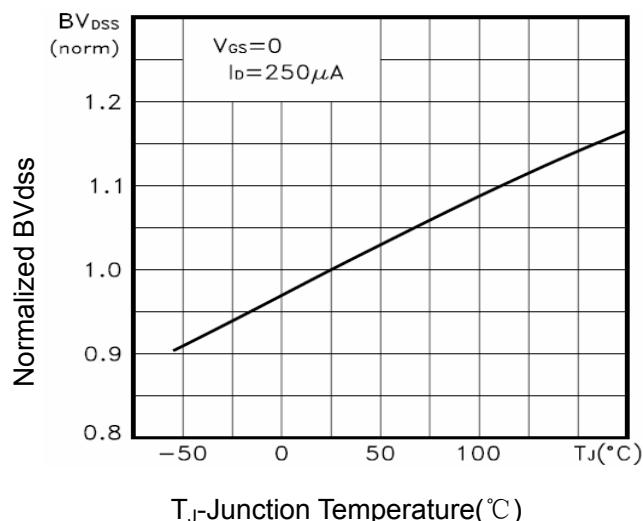


Figure 9  $BV_{dss}$  vs Junction Temperature

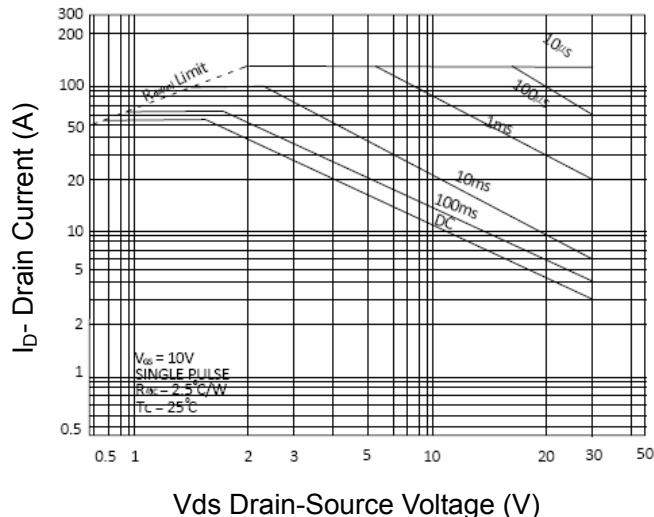


Figure 8 Safe Operation Area

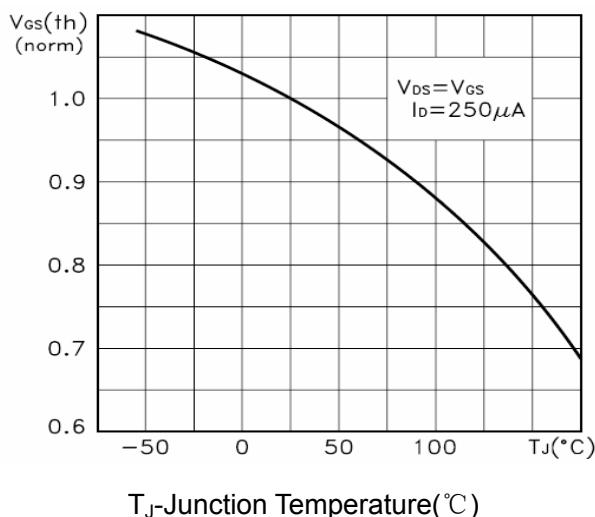


Figure 10  $V_{gs(th)}$  vs Junction Temperature

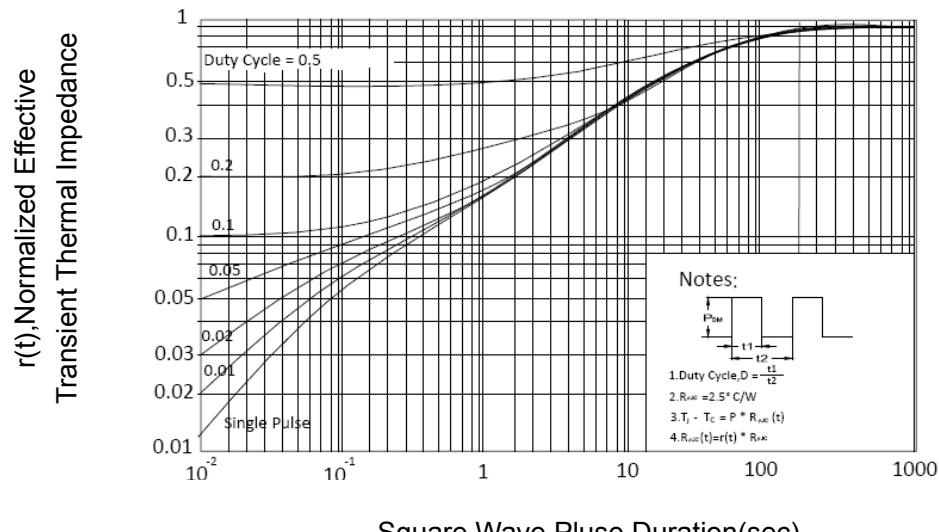
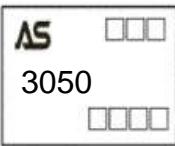
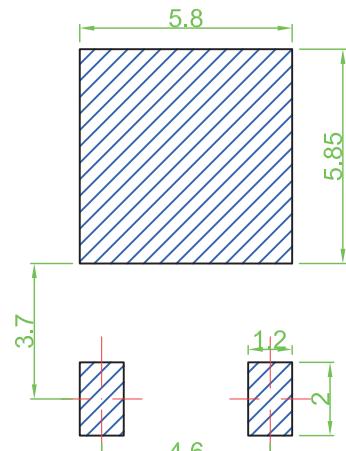
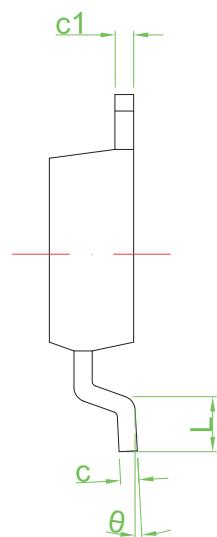
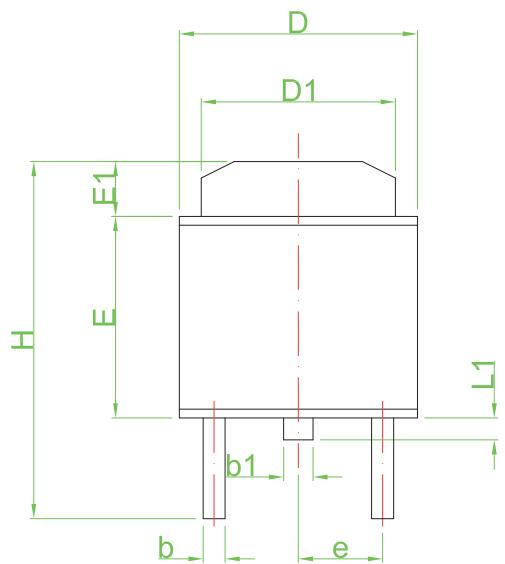


Figure 11 Normalized Maximum Transient Thermal Impedance

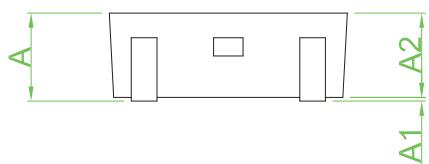
## Ordering and Marking Information

Ordering Device No.	Marking	Package	Packing	Quantity
ASDM3050KQ-R	3050	TO-252	Tape&Reel	2500

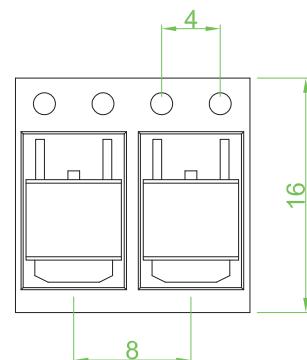
PACKAGE	MARKING
TO-252	 AS      □□□ → Lot Number 3050    □□□ → Date Code



Recommended Land Pattern



Symbol	Dimensions in Millimeters		Dimensions in Inches	
	Min	Max	Min	Max
A	2.25	2.65	0.089	0.104
A1	0.00	0.15	0.000	0.006
A2	2.20	2.40	0.087	0.094
b	0.50	0.70	0.020	0.028
b1	0.70	0.90	0.028	0.035
c	0.46	0.66	0.018	0.026
c1	0.46	0.66	0.018	0.026
D	6.30	6.70	0.248	0.264
D1	5.20	5.40	0.205	0.213
E	5.30	5.70	0.209	0.224
E1	1.40	1.60	0.055	0.063
H	9.40	9.90	0.370	0.390
e	2.30 TYP		0.09 TYP	
L	1.40	1.77	0.055	0.070
L1	0.50	0.70	0.020	0.028
θ	0°	8°	0°	8°



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